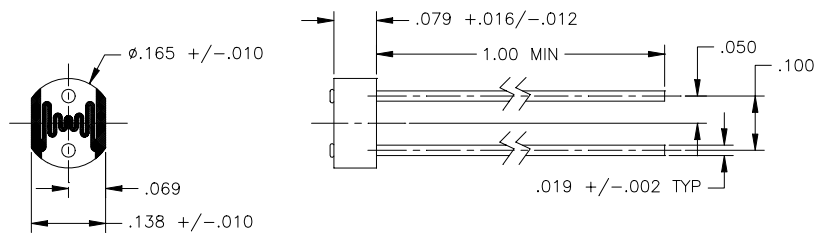


CL9P5LQ

Epoxy-encapsulated Photoconductors (Replaces the CL9P5L)



November, 2003



Pattern shown is
typical and may vary
from part to part.

ALL DIMENSIONS ARE IN INCHES

features

- thicker ceramic substrate
- low cost epoxy encapsulation

description

The CL9P5LQ consists of CdS base material deposited on a ceramic substrate and epoxy encapsulated. The CL9P5LQ is electrically equivalent to, and replaces, the CL9P5L and CL905L. For applications assistance, call Clairex.

absolute maximum ratings ($T_A = 25^\circ\text{C}$ unless otherwise stated)

storage and operating temperature -50°C to $+75^\circ\text{C}$
lead soldering temperature⁽¹⁾ 260°C
power dissipation at 25°C air temperature 50mW

notes:

1. 0.06" (1.5mm) from the case for 5 seconds maximum.
2. The CL9P5LQ has a 0.079" thick substrate and 1.0" minimum length leads. The CL9P5L had a 0.055" thick substrate and 1.4" minimum length leads.

electrical characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Part Number	Material Type	$R_{ON}^{(1)(2)}$ $\Omega(\text{typ})$	$R_{OFF}^{(3)}$ $\Omega(\text{min.})$	$V_{\text{meas}}^{(4)}$ Volts	$V_{(\text{max})}$ Volts
CL9P5LQ	CdS, CdSe	10K	670K	10	100

- notes:**
1. On-resistance (R_{ON}) is measured at 2 ft-c after light stabilization at 30 ft-c for 16 hours minimum just prior to test. R_{ON} tolerance is $\pm 33\%$ at 2 ft-c.
 2. Light source for all R_{ON} measurements is an unfiltered tungsten source operating at a color temperature of 2854K.
 3. Off-resistance (R_{OFF}) is measured under dark conditions, 5 seconds after R_{ON} test. A dark condition is reached when the value of R_{OFF} can not be increased by further irradiation shielding.
 4. Measurement voltage (V_{meas}) is the steady-state bias applied to the device for measurement of R_{ON} and R_{OFF} .